

March 2013

FQT5P10

P-Channel QFET® MOSFET

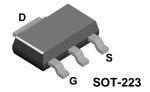
-100 V, -1.0 A, 1.05 Ω

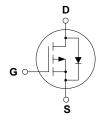
Description

This P-Channel enhancement mode power MOSFET is produced using Fairchild Semiconductor®'s proprietary planar stripe and DMOS technology. This advanced MOSFET technology has been especially tailored to reduce on-state resistance, and to provide superior switching performance and high avalanche energy strength. These devices are suitable for switched mode power supplies, audio amplifier, DC motor control, and variable switching power applications.

Features

- -1.0 A, -100 V, $R_{DS(on)}$ =1.05 $\Omega(Max.)$ @ V_{GS} =-10 V, I_D =-0.5 A
- Low Gate Charge (Typ. 6.3 nC)
- Low Crss (Typ. 18 pF)
- 100% Avalanche Tested





Absolute Maximum Ratings T_C = 25°C unless otherwise noted

| Symbol | Parameter | | FQT5P10 | Unit | |
|-----------------------------------|---|----------|-------------|------|--|
| V _{DSS} | Drain-Source Voltage | | -100 | V | |
| I _D | Drain Current - Continuous (T _C = 25°C) | | -1.0 | А | |
| | - Continuous (T _C = 70° | °C) | -0.8 | А | |
| I _{DM} | Drain Current - Pulsed | (Note 1) | -4.0 | А | |
| V _{GSS} | Gate-Source Voltage | | ± 30 | V | |
| E _{AS} | Single Pulsed Avalanche Energy | (Note 2) | 55 | mJ | |
| I _{AR} | Avalanche Current | (Note 1) | -1.0 | А | |
| E _{AR} | Repetitive Avalanche Energy | (Note 1) | 0.2 | mJ | |
| dv/dt | Peak Diode Recovery dv/dt | (Note 3) | -6.0 | V/ns | |
| P _D | Power Dissipation (T _C = 25°C) | | 2.0 | W | |
| | - Derate above 25°C | | 0.016 | W/°C | |
| T _J , T _{STG} | Operating and Storage Temperature Range | | -55 to +150 | °C | |
| T _L | Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds | | 300 | °C | |

Thermal Characteristics

| Symbol | Parameter | Тур | Max | Unit |
|-----------------|---|-----|------|------|
| $R_{\theta JA}$ | Thermal Resistance, Junction-to-Ambient * | | 62.5 | °C/W |

^{*} When mounted on the minimum pad size recommended (PCB Mount)

| Symbol | Parameter | Test Conditions | Min | Тур | Max | Unit |
|---|---|--|------|------|------|------|
| Off Cha | racteristics | | | | | |
| BV _{DSS} | Drain-Source Breakdown Voltage | $V_{GS} = 0 \text{ V, } I_D = -250 \mu\text{A}$ | -100 | | | V |
| ΔB _{VDSS} / ΔΤ _J | Breakdown Voltage Temperature Coefficient | I _D = -250 μA, Referenced to 25°C | | -0.1 | | V/°C |
| I _{DSS} | Zero Gate Voltage Drain Current | V _{DS} = -100 V, V _{GS} = 0 V | | | -1 | μΑ |
| | | V _{DS} = -80 V, T _C = 125°C | | | -10 | μΑ |
| I _{GSSF} | Gate-Body Leakage Current, Forward | V _{GS} = -30 V, V _{DS} = 0 V | | | -100 | nA |
| I _{GSSR} | Gate-Body Leakage Current, Reverse | V _{GS} = 30 V, V _{DS} = 0 V | | | 100 | nA |
| On Cha | racteristics | | | | | |
| V _{GS(th)} | Gate Threshold Voltage | $V_{DS} = V_{GS}, I_{D} = -250 \mu\text{A}$ | -2.0 | | -4.0 | V |
| R _{DS(on)} | Static Drain-Source On-Resistance | V _{GS} = -10 V, I _D = -0.5 A | | 0.82 | 1.05 | Ω |
| 9 _{FS} | Forward Transconductance | $V_{DS} = -40 \text{ V}, I_D = -0.5 \text{ A}$ (Note 4) | | 1.4 | | S |
| Dynam C _{iss} | ic Characteristics Input Capacitance | V _{DS} = -25 V, V _{GS} = 0 V, | | 190 | 250 | pF |
| C _{oss} | Output Capacitance | f = 1.0 MHz | | 70 | 90 | pF |
| C _{rss} | Reverse Transfer Capacitance | - · · · · · · · · · · · · · · · · · · · | | 18 | 25 | pF |
| Switchi | ng Characteristics | | • | | | |
| t _{d(on)} | Turn-On Delay Time | V 50 V I 45 A | | 9 | 30 | ns |
| t _r | Turn-On Rise Time | $V_{DD} = -50 \text{ V}, I_{D} = -4.5 \text{ A},$ $R_{G} = 25 \Omega$ | | 70 | 150 | ns |
| t _{d(off)} | Turn-Off Delay Time | NG - 20 32 | | 12 | 35 | ns |
| t _f | Turn-Off Fall Time | (Note 4, 5 | | 30 | 70 | ns |
| Qg | Total Gate Charge | $V_{DS} = -80 \text{ V}, I_{D} = -4.5 \text{ A},$ | | 6.3 | 8.2 | nC |
| Q _{gs} | Gate-Source Charge | V _{GS} = -10 V | | 1.7 | | nC |
| Q _{gd} | Gate-Drain Charge | (Note 4, 5 | | 3.0 | | nC |
| Drain-S | ource Diode Characteristics a | nd Maximum Ratings | | | | |
| I _S | Maximum Continuous Drain-Source Diode Forward Current | | | | -1.0 | Α |
| I _{SM} | Maximum Pulsed Drain-Source Diode Forward Current | | | | -4.0 | Α |
| V _{SD} | Drain-Source Diode Forward Voltage | V _{GS} = 0 V, I _S = -1.0 A | | | -4.0 | V |
| trr | Reverse Recovery Time | $V_{GS} = 0 \text{ V, } I_{S} = -4.5 \text{ A,}$ | | 85 | | ns |
| Qrr | Reverse Recovery Charge | $dI_F / dt = 100 A/\mu s$ (Note 4) | | 0.27 | | μC |

- Notes: 1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 83mH, I_{AS} = -1.0A, V_{DD} = -25V, R_G = 25 Ω . Starting T_J = 25°C 3. I_{SD} ≤ -4.5A, di/dt ≤ 300A/ μ s, V_{DD} ≤ BV $_{DSS}$, Starting T_J = 25°C 4. Pulse Test : Pulse width ≤ 300 μ s, Duty cycle ≤ 2% 5. Essentially independent of operating temperature

Typical Characteristics

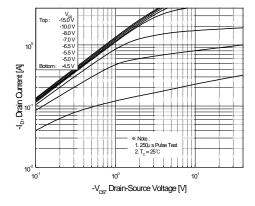


Figure 1. On-Region Characteristics

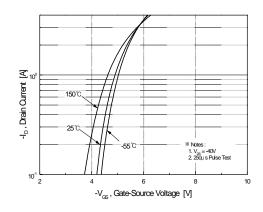


Figure 2. Transfer Characteristics

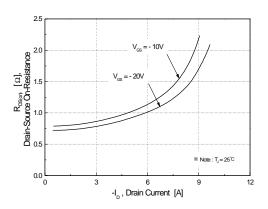


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

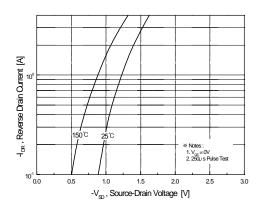


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

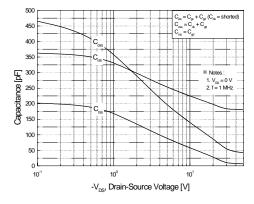


Figure 5. Capacitance Characteristics

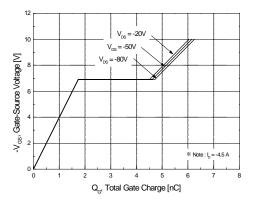
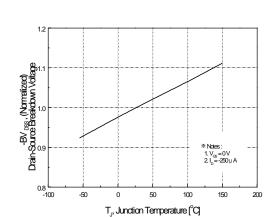


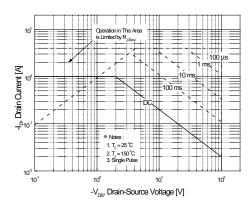
Figure 6. Gate Charge Characteristics



Typical Characteristics (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

Figure 8. On-Resistance Variation vs. Temperature



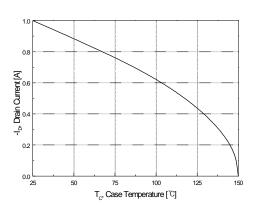


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs. Case Temperature

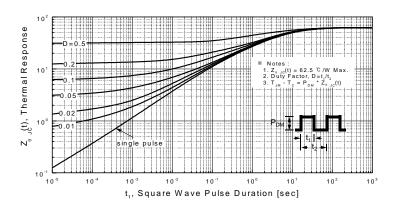
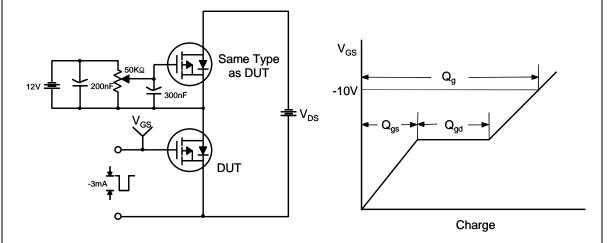
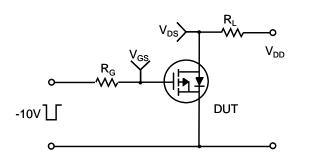


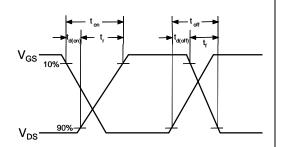
Figure 11. Transient Thermal Response Curve

Gate Charge Test Circuit & Waveform

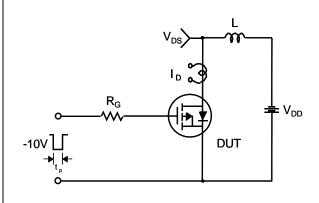


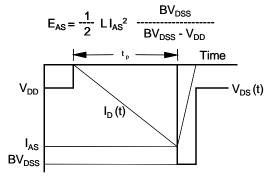
Resistive Switching Test Circuit & Waveforms



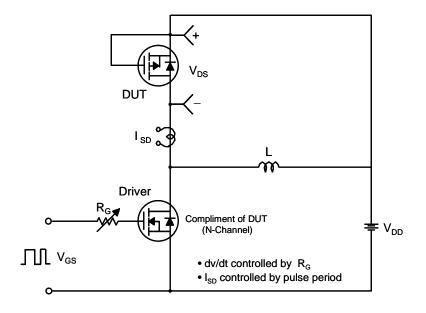


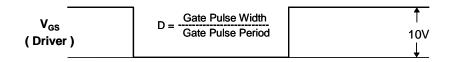
Unclamped Inductive Switching Test Circuit & Waveforms

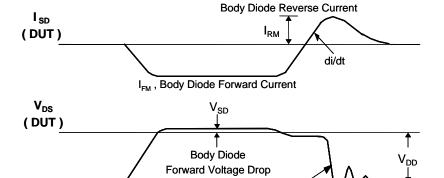




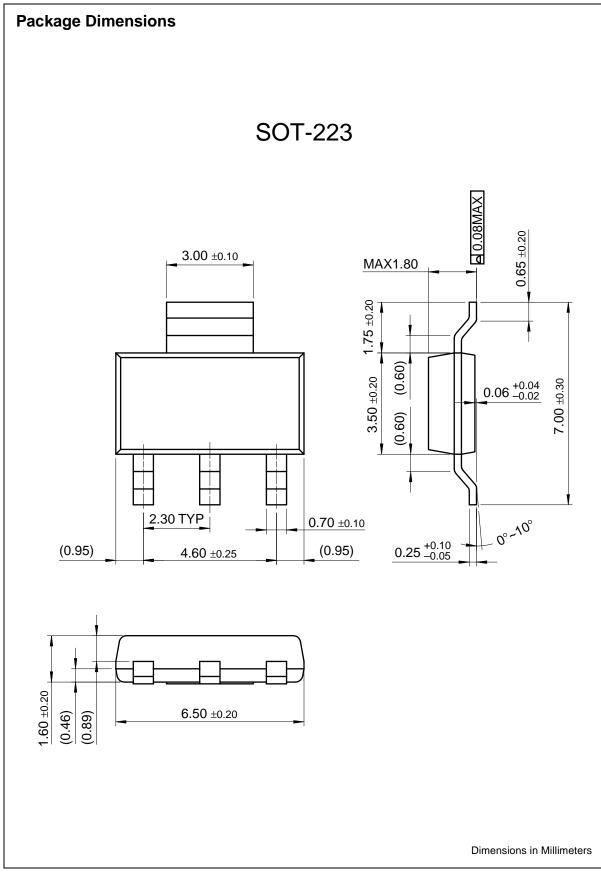
Peak Diode Recovery dv/dt Test Circuit & Waveforms







Body Diode Recovery dv/dt







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